

Scanning Spectrometer



SIR-2600 Compact, Extended Range Spectrometer

The SIR-2600 Scanning Spectrometer collects spectral data from 0.9 μm to 2.6 μm wavelength range. The SIR2600's fiber-based system uses a unique design that allows rapid spectral scans over its entire range. It can also provide real-time data from several discrete wavelengths. The compact design allows you to integrate the SIR-2600 easily into OEM applications and online process environments.

The SIR-2600 uses a single point detector and a high angular resolution-tunable grating system. The zero-backlash mechanical design provides superior accuracy and repeatability. This combination, along with an innovative 24-bit A/D converter, provides high spectral resolution and very high signal-to-noise data.

An optional filter wheel provides optical order sorting of diffracted orders.

The SIR-2600 is designed with a rugged aluminum housing that is robust enough to withstand the rigors of chemical processing applications.

The USB 2.0-compliant interface provides fast data transfers and our included software can be used to control all of the SIR-2600's functions as well as analyze data.

Specifications

Range:	0.9 μm - 2.6 μm
Detector:	Extended Range InGaAs with 2-stage cooler
Diffraction grating:	600 lines/mm 1.5 μm blaze
Optical design:	Czerny-Turner F/3
Slits available:	10 μm , 50 μm , 100 μm , 200 μm , 500 μm
Optical input:	SMA-905/906 with optional lensed input
Analog resolution:	24 bits 16,777,216 counts
Triggering options:	Internal and external synchronization, pulse width control and phase delay
Additional digital outputs:	2 channel selectable 3.3V/5V output
Additional digital inputs:	2 channels 3.3V/5V compatible inputs
Grating steps in range:	45000
Step accuracy:	+/- 10 steps
Data interface:	USB 2.0
Scan time:	As quick as 20 seconds
Resolution based on optical slits:	

JT Ingram Technologies
www.jtingram.com
jim@jtingram.com
800 335 5582

